



## Gallium Nitride 28V 15W, RF Power Transistor

### Description

The GTAH58015GX is a 15W, internally matched GaN HEMT, designed for multiple applications, especially sub-6GHz LTE/LTE-A/LTE-U from 4500-5900MHz.

There is no guarantee of performance when this part is used in applications designed Outside of these frequencies.

- Typical performance (on narrow band fixture with device soldered)

$V_{DD}=28V$   $I_{DQ}=110mA$ , Pulse CW, Pulse width=20uS, Duty cycle=20%.

Frequency(MHz)	Gp (dB)	$P_{SAT}(W)$	Efficiency (%)
5725	13.9	18.6	57.6
5800	14.4	19.5	64.3
5925	14.6	17.0	57.1

- Typical performance (on narrow band fixture with device soldered)

$V_{DD} = 28$  Volts,  $IDQ = 110$  mA, Test signal: WCDMA, 3GPP test model 1; 1 to 64 DPCH; Channel Bandwidth=3.84MHz, PAR =10.5 dB at 0.01 % probability on CCDF.

Frequency (MHz)	$P_{L(AV)}$ (W)	Gp (dB)	$\eta_D$ (%)	ACPR <sub>5M</sub> (dBc)
5725	2	13.6	23.8	-40.8
5800	2	14.0	26.4	-41.2
5925	2	14.1	25.3	-41.1

### Applications and Features

- Suitable for wireless communication infrastructure, wideband amplifier, EMC testing, ISM etc.
- High Efficiency and Linear Gain Operations
- Thermally Enhanced Industry Standard Package
- High Reliability Metallization Process
- Excellent thermal Stability and Excellent Ruggedness
- Compliant to Restriction of Hazardous Substances (RoHS) Directive 2002/95/EC

### Important Note: Proper Biasing Sequence for GaN HEMT Transistors

#### Turning the device ON

1. Set VGS to the pinch-off (VP) voltage, typically -5 V
2. Turn on VDS to nominal supply voltage (28V)
3. Increase VGS until IDS current is attained
4. Apply RF input power to desired level

#### Turning the device OFF

1. Turn RF power off
2. Reduce VGS down to VP, typically -5 V
3. Reduce VDS down to 0 V
4. Turn off VGS

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain--Source Voltage	$V_{DSS}$	150	Vdc
Gate--Source Voltage	$V_{GS}$	-10,+2	Vdc
Operating Voltage	$V_{DD}$	40	Vdc
Maximum Forward Gate Current @ $T_C = 25^\circ C$	$I_{gmax}$	4	mA

**GTAH58015GX**





Storage Temperature Range	T <sub>stg</sub>	-65 to +150	°C
Case Operating Temperature	T <sub>c</sub>	+150	°C
Operating Junction Temperature(See note 1)	T <sub>j</sub>	+200	°C
Total Device Power Dissipation (Derated above 25°C, see note 2)	P <sub>diss</sub>	31	W

Note: 1. Continuous operation at maximum junction temperature will affect MTTF

2. Bias Conditions should also satisfy the following expression:  $P_{diss} < (T_j - T_c) / R_{JC}$  and  $T_c = T_{case}$

**Table 2. Thermal Characteristics**

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case T <sub>C</sub> = 85°C, T <sub>J</sub> =200°C, RF CW operation	R <sub>θJC</sub>	5.67	C/W

**Table 3. Electrical Characteristics** (T<sub>C</sub> = 25°C unless otherwise noted)

**DC Characteristics**

Characteristic	Conditions	Symbol	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V <sub>GS</sub> =-8V; I <sub>DS</sub> =4mA	V <sub>DSS</sub>	150			V
Gate Threshold Voltage	V <sub>DS</sub> = 28V, I <sub>D</sub> = 4mA	V <sub>GS(th)</sub>		-2.7		V
Gate Quiescent Voltage	V <sub>DS</sub> =28V, I <sub>DS</sub> =110mA, Measured in Functional Test	V <sub>GS(Q)</sub>		-2.4		V

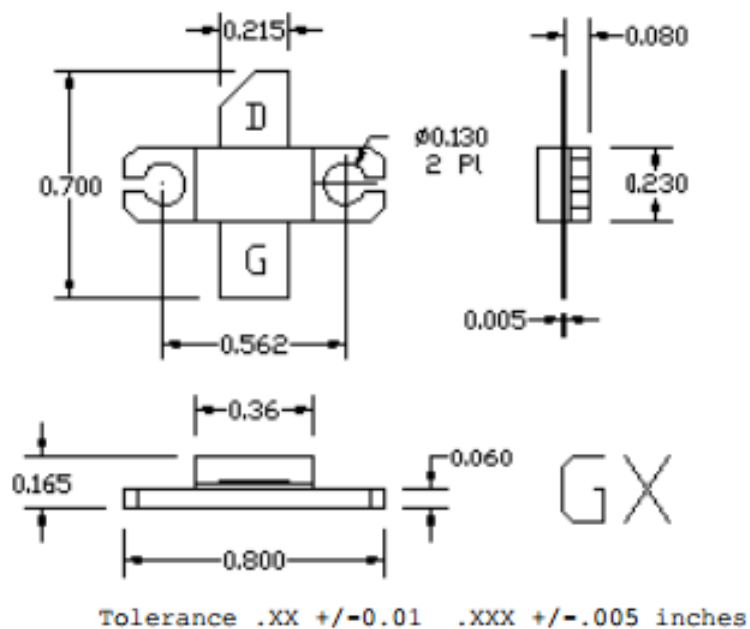
**Functional Tests (In 5.7-5.9GHz Production Test Fixture, 50 ohm system)** :V<sub>DD</sub> = 28 Vdc, I<sub>DQ</sub> = 110 mA, f = 5800 MHz, WCDMA signal,  
P<sub>out</sub>=2W

Characteristic	Symbol	Min	Typ	Max	Unit
Power Gain	G <sub>p</sub>		14		dB
Drain Efficiency @ P <sub>SAT</sub>	Eff		26		%
Saturated Power by CCDF test	P <sub>SAT</sub>	15			W
Input Return Loss	IRL		-10		dB
Mismatch stress at all phases (Device no damage)	VSWR		10:1		Ψ



## Package Outline

Flanged ceramic package; 2 leads



OUTLINE VERSION	REFERENCE			EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA		
PKG-G2E					03/12/2013

Figure 1. Package Outline PKG-G2E



## Revision history

Table 4. Document revision history

Date	Revision	Datasheet Status
2017/4/27	V1.0	Preliminary Datasheet Creation
2017/5/25	V1.1	Preliminary Datasheet
2017/6/20	V1.2	Modification on maximum rating

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